

14A, 60V N-CHANNEL MOSFET

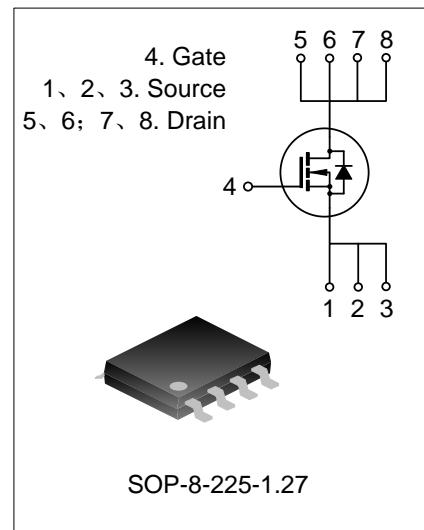
DESCRIPTION

SVGP069R5NSA is an N-channel enhancement mode power MOS field effect transistor which is produced using Silan's LVMOS technology. The improved process and cell structure have been especially tailored to minimize on-state resistance, provide superior switching performance.

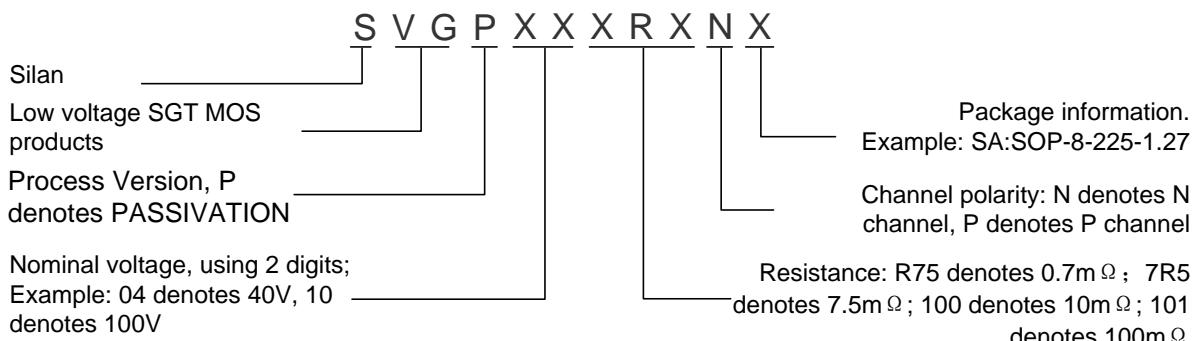
This device is widely used in Secondary synchronous rectifier, Power Management for Inverter Systems.

FEATURES

- 14A, 60V, $R_{DS(on)(typ.)}=8m\Omega$ @ $V_{GS}=10V$
- Low gate charge
- Low Crss
- Fast switching
- Improved dv/dt capability



NOMENCLATURE



ORDERING INFORMATION

Part No.	Package	Marking	Hazardous Substance Control	Packing Type
SVGP069R5NSA	SOP-8-225-1.27	P069R5	Halogen free	Tube
SVGP069R5NSATR	SOP-8-225-1.27	P069R5	Halogen free	Tape&Reel



ABSOLUTE MAXIMUM RATINGS (Unless otherwise noted, $T_c=25^\circ\text{C}$)

Characteristics		Symbol	Ratings	Unit
Drain-Source Voltage		V_{DS}	60	V
Gate-Source Voltage		V_{GS}	± 20	V
Drain Current	$T_c=25^\circ\text{C}$	I_D	14	A
	$T_c=100^\circ\text{C}$		9	
Drain Current Pulsed		I_{DM}	56	A
Power Dissipation($T_c=25^\circ\text{C}$) -Derate above 25°C		P_D	3.2	W
			0.03	W/°C
Single Pulsed Avalanche Energy(Note 1)		E_{AS}	81	mJ
Operation Junction Temperature Range		T_J	-55~+150	°C
Storage Temperature Range		T_{stg}	-55~+150	°C

THERMAL CHARACTERISTICS

Characteristics	Symbol	Ratings	Unit
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	39	°C/W
Thermal Resistance, Junction-to-Ambient	$R_{\theta JA}$	85	°C/W

ELECTRICAL CHARACTERISTICS (Unless otherwise noted, $T_c=25^\circ\text{C}$)

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Drain -Source Breakdown Voltage	BV_{DSS}	$V_{GS}=0\text{V}$, $I_D=250\mu\text{A}$	60	--	--	V
Drain-Source Leakage Current	I_{DSS}	$V_{DS}=60\text{V}$, $V_{GS}=0\text{V}$	--	--	1.0	μA
Gate-Source Leakage Current	I_{GSS}	$V_{GS}=\pm 20\text{V}$, $V_{DS}=0\text{V}$	--	--	± 100	nA
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{GS}=V_{DS}$, $I_D=250\mu\text{A}$	1.4	--	2.5	V
Static Drain- Source On State Resistance	$R_{DS(\text{on})}$	$V_{GS}=10\text{V}$, $I_D=13.5\text{A}$	--	8	9.5	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}$, $I_D=11.5\text{A}$	--	11	13.5	$\text{m}\Omega$
Gate Resistance	R_G	f=1MHz	--	1.8	--	Ω
Input Capacitance	C_{iss}	f=1MHz, $V_{GS}=0\text{V}$, $V_{DS}=30\text{V}$	--	1061	--	pF
Output Capacitance	C_{oss}		--	432	--	
Reverse Transfer Capacitance	C_{rss}		--	23	--	
Turn-on Delay Time	$t_{d(\text{on})}$	$V_{DD}=30\text{V}$, $V_{GS}=10\text{V}$, $R_G=3\Omega$, $I_D=13.5\text{A}$	--	8.0	--	ns
Turn-on Rise Time	t_r		--	54	--	
Turn-off Delay Time	$t_{d(\text{off})}$		--	19	--	
Turn-off Fall Time	t_f		--	8.8	--	
Total Gate Charge	Q_g	$V_{DD}=48\text{V}$, $V_{GS}=10\text{V}$, $I_D=13.5\text{A}$	--	17	--	nC
Gate-Source Charge	Q_{gs}		--	5.8	--	
Gate-Drain Charge	Q_{gd}		--	2.6	--	



SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Continuous Source Current	I _S	Integral Reverse P-N Junction Diode in the MOSFET	--	--	14	A
Pulsed Source Current	I _{SM}		--	--	56	
Diode Forward Voltage	V _{SD}	I _S =13.5A, V _{GS} =0V	--	--	1.4	V
Reverse Recovery Time	T _{rr}	I _S =13.5A, V _{GS} =0V,	--	52	--	ns
Reverse Recovery Charge	Q _{rr}	dI/dt=100A/μs (Note 2)	--	0.05	--	μC

Notes:

- 1.L=0.5mH, V_{DD}=50V, R_G=10Ω, starting T_J=25°C;
- 2.Pulse Test: Pulse width ≤300μs,Duty cycle≤2%;
- 3.Essentially independent of operating temperature.



TYPICAL CHARACTERISTICS

Figure 1. Output Characteristics

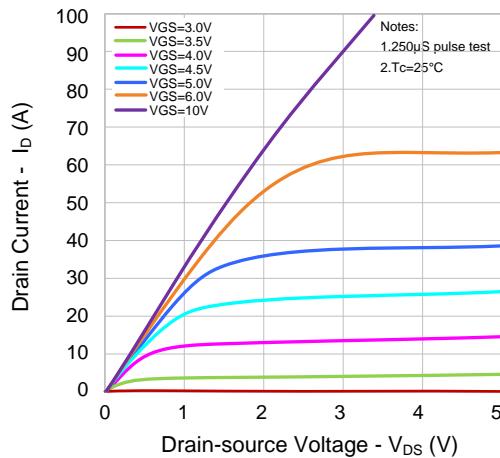


Figure 2. Transfer Characteristics

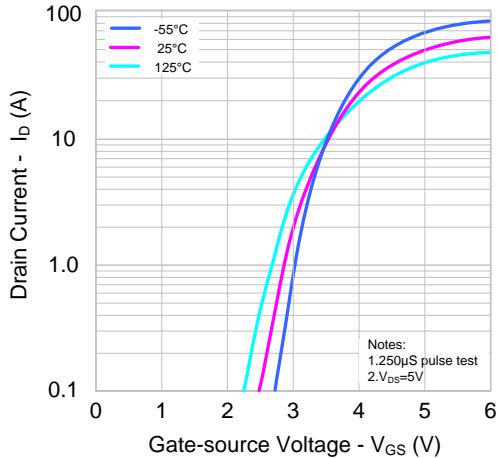


Figure 3. On-resistance vs. Drain Current

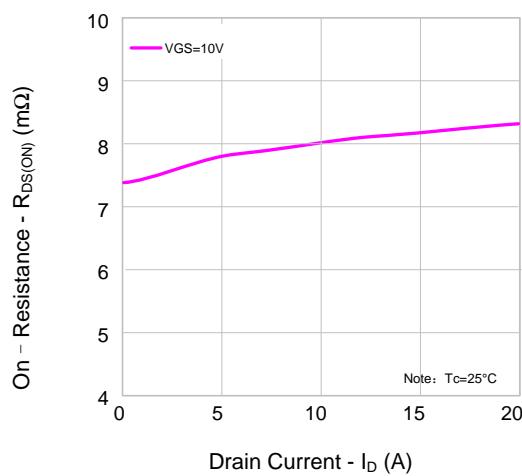


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

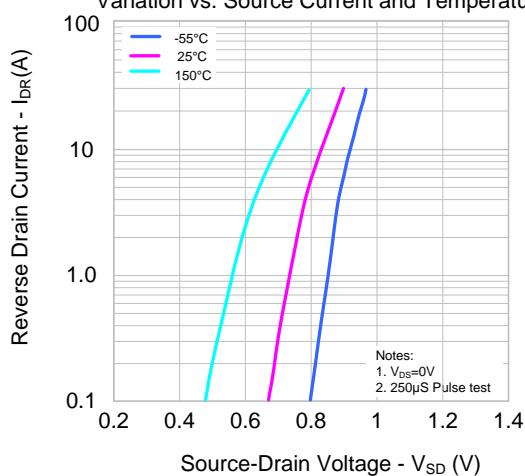


Figure 5. Capacitance Characteristics

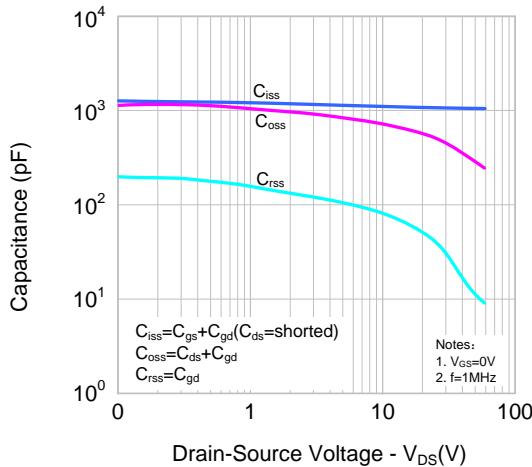
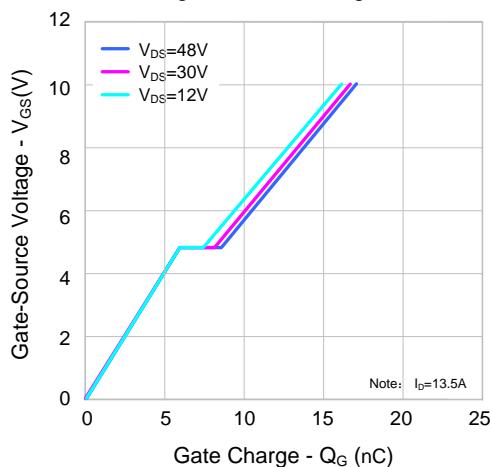
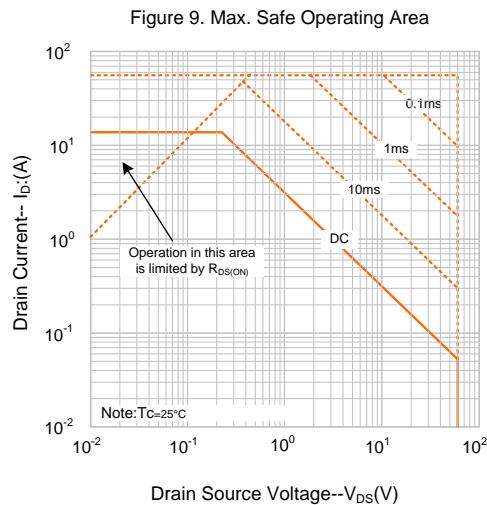
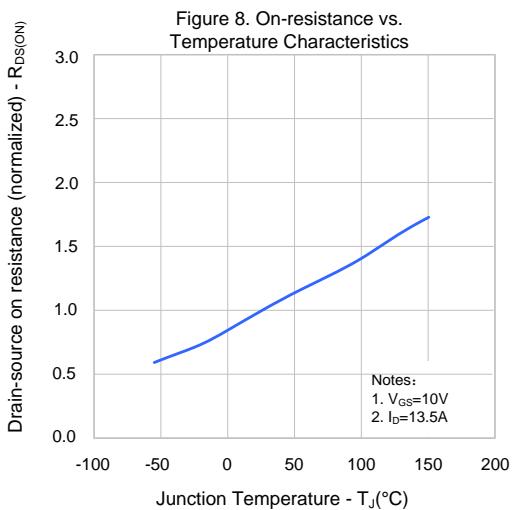
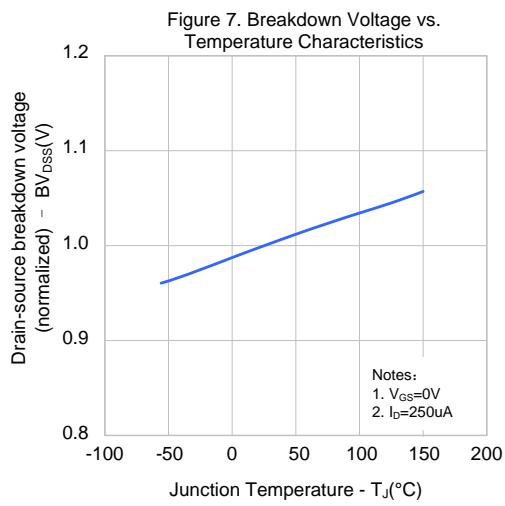


Figure 6. Gate Charge



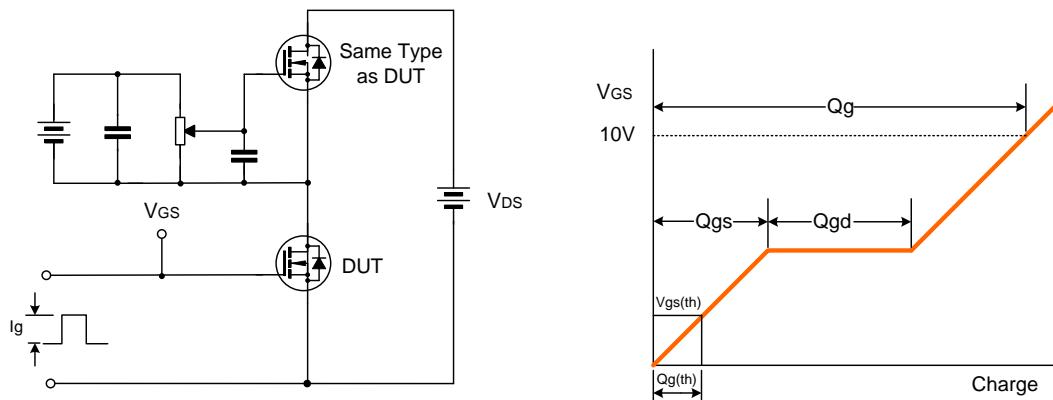


TYPICAL CHARACTERISTICS(continued)

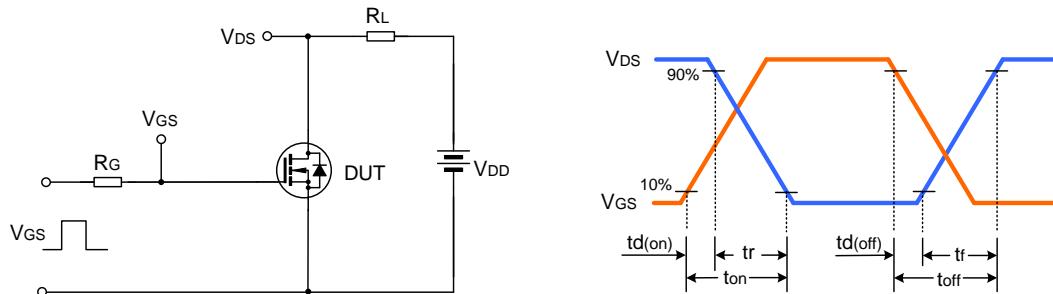




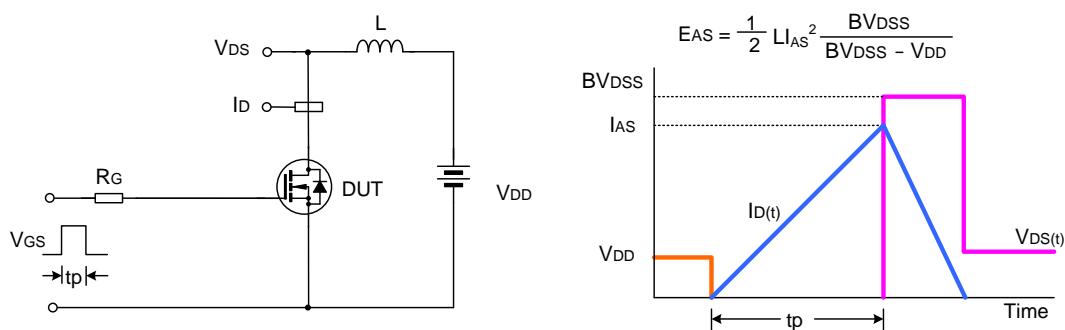
TYPICAL TEST CIRCUIT



Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveform

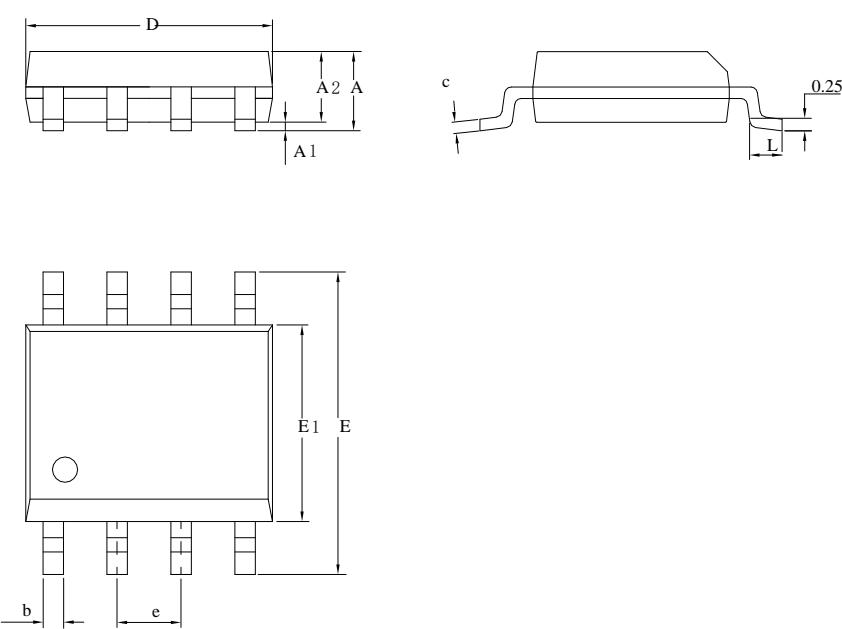


Unclamped Inductive Switching Test Circuit & Waveform



PACKAGE OUTLINE

SOP-8-225-1.27		UNIT: mm		
SYMBOL	MILLIMETER			
	MIN	NOM	MAX	
A	1.35	1.55	1.75	
A1	0.05	0.15	0.25	
A2	1.25	--	1.65	
b	0.32	0.42	0.52	
c	0.15	0.2	0.26	
D	4.70	4.90	5.30	
E	5.60	6.00	6.40	
E1	3.60	3.90	4.20	
e	1.27BSC			
L	0.30	—	1.27	



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Revision History:

1. Update Electrical schematic
 2. Update TYPICAL TEST CIRCUIT
 3. Update important notice

Rev.:

1.1

Revision History:

- #### 1. Modify electrical characteristics

Rev.:

1.0

Revision History

- ## 1 First release